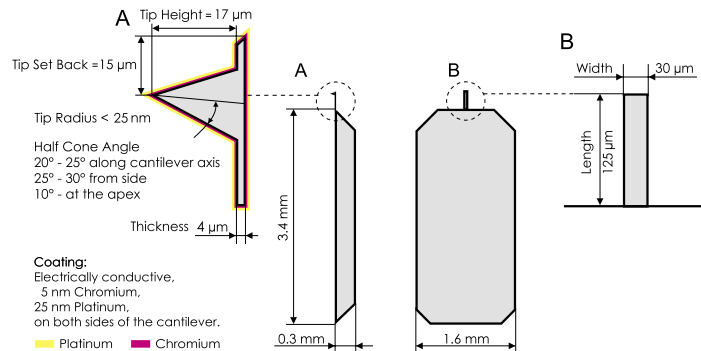




# AFM probe Model: *ElectriTap300*



- Tapping, Intermittent Contact and Electric Modes like:
  - Scanning Capacitance Microscopy (SCM)
  - Electrostatic Force Microscopy (EFM)
  - Kelvin probe Force Microscopy (KFM)
  - Scanning probe lithography
- Rotated Monolithic Silicon Probe Symmetric Tip Shape  
Chipsize: 3.4 x 1.6 x 0.3 mm
- Coating: Electrically conductive coating of 5 nm Chromium and 25 nm Platinum on both sides of the cantilever. This coating also enhances the laser reflectivity of the cantilever
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.



	Typical Values	Range
Resonant Frequency	300 kHz	+/- 100 kHz
Force Constant	40 N/m	20 - 75 N/m
Cantilever Length	125 $\mu\text{m}$	+/- 10 $\mu\text{m}$
Mean Width	30 $\mu\text{m}$	+/- 5 $\mu\text{m}$
Thickness	4 $\mu\text{m}$	+/- 1 $\mu\text{m}$
Tip Height	17 $\mu\text{m}$	+/- 2 $\mu\text{m}$
Tip Set Back	15 $\mu\text{m}$	+/- 5 $\mu\text{m}$
Tip Radius	< 25 nm	
Coating	Cr/Pt on both sides	
Half Cone Angle	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	
Contact Resistance	300 Ohms on platinum thin film surface	

Order Code	Units in Package	Coating	Price
Tap300E-10	10 pieces	Chrome / Platinum	\$240
Tap300E-50	50 pieces	Chrome / Platinum	\$1000